Examiner-Initiated Interview Summa		Application No.	Applicant(s)
	narv	10/603,983	HASEGAWA ET AL.
	iiai y	Examiner	Art Unit
		Kevin M Bernatz	1773
All Participants:		Status of Application	on:
(1) <u>Kevin M Bernatz</u> .		(3)	
(2) <u>Gustavo Siller</u> .		(4)	•
Date of Interview: 24 June 2005		Time: <u><i>AM</i></u>	
	☐ Applic] No	ant's representative)	
Part I.			
Rejection(s) discussed: all			
Claims discussed: 1,30			
Prior art documents discussed: N/A			
Part II.			
SUBSTANCE OF INTERVIEW DESCRIBING TO See Continuation Sheet	HE GENE	RAL NATURE OF WHA	T WAS DISCUSSED:
Part III.	•		
 It is not necessary for applicant to provide a directly resulted in the allowance of the applic of the interview in the Notice of Allowability. It is not necessary for applicant to provide a did not result in resolution of all issues. A brief 	cation. Th separate	e examiner will provide record of the substance	a written summary of the substance of the interview, since the interview
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Him por			
(Examiner/SPE Signature)	(Applican	t/Applicant's Representa	tive Signature – if appropriate)

Continuation of Substance of Interview including description of the general nature of what was discussed: The Examiner indicated that positively reciting that the present sensor was a current-in-plane (CiP) type sensor wherein the electrode layers are in contact with the side portions of the multilayer film along the track width direction would distinguish over the prior art CPP structures wherein the electrodes are offset from the multilayer film in the track width direction. The Examiner further noted that the positive recitation of "current-in-plane" insured that the scope afforded to the term "electrode layers" must function to provide a current in the plane of the films and would not be read on by non-magnetic underlayers, etc. which happened to be formed of materials typically used as conductive electrodes/leads in MR sensors.